


<b>Search Notes</b> 	<b>Application/Control No.</b> 10763224	<b>Applicant(s)/Patent Under Reexamination</b> CHO, BYOUNG-WOO
	<b>Examiner</b> Haney, Richale L	<b>Art Unit</b> 3765

SEARCHED			
Class	Subclass	Date	Examiner
2	181, 195.1	08/03/2006	RLH
above	updated	2/2/2007	RLH

SEARCH NOTES		
Search Notes	Date	Examiner
See EAST search printout	08/03/2006	RLH

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner